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				Application Number	10/576,342
				Filing Date	April 18, 2006
				First Named Inventor	DELATTRE, Cyril
				Art Unit	1641
				Examiner Name	LAM, Ann Y.
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Sheet	1	of	1		

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No.*	Document Number Number-Kind Code <sup>3</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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CA	LEE, Junghoon, et al.,	Electrowetting And Electrowetting-On-Dielectric For Microscale Liquid Handling, <i>Sensors and Actuators A</i> 95 (2002), pp. 259-268.			
CB	BRATTEN, Craig D. T., et al.,	Micromachining Sensors for Electrochemical Measurement in Subnanoliter Volumes, <i>Anal. Chem.</i> 1997, 69, pp. 253-258.			
CC	YANG, Mengsu, et al.	Covalent Immobilization of Oligonucleotides on Modified Glass/Silicon Surfaces for Solid-Phase DNA Hybridization and Amplification, <i>Chemistry Letters</i> 1998, pp. 257-258.			
CD	BONCHEVA, Mila, et al.,	Design of Oligonucleotide Arrays at Interfaces, <i>Langmuir</i> 1999, 15, pp. 4317-4320.			
CE	JANSEN, Henri, et al.,	The Black Silicon Method: A Universal Method for Determining the Parameter Setting of a Fluorine-Based Reactive Ion Etcher In Deep Silicon Trench Etching With Profile Control, <i>J. Micromech. Microeng.</i> 5 (1995) pp. 115-120.			

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Examiner Signature	/Ann Lam/	Date Considered	02/28/2010
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